Abstract

A method, apparatus and article of manufacture to aid in the characterization of a device establishes a device S-parameter matrix (S_D) to represent electrical behavior of the device, an adapter T-parameter matrix (T_a) to represent all possible electrical paths through circuits to all device ports of the device, and a cascaded S-parameter matrix (S_c) to represent the circuits cascaded with the device. Values for the adapter T-parameter matrix are obtained either through measurement or modeling. The device cascaded with the circuits is measured to obtain values for the cascaded S-parameter matrix, permitting use of a general solution for the device S-parameter matrix as a function of the adapter T-parameter matrix and the cascaded S-parameter matrix.